

# Cleanliness Related Efforts in IPC Standards

# Determining How Clean is Clean

Doug Pauls Rockwell Collins Chairman, Cleaning and Coating Committees







## 5-31: Cleaning Alternatives

#### • 5-31: Cleaning and Alternatives

- 5-31a Solvent Cleaning TG
  5-31b Semi-Aqueous Cleaning TG
  5-31c Aqueous Cleaning TG
  5-31c Cleaning Handbook TG
  5-31d Cleaning Handbook TG
  5-31g Stencil Cleaning Handbook
- New Revision Efforts Starting (Fall 2007)
  - Chairman, Mike Bixenman, Kyzen Corporation
  - The Cleaning Handbooks (4) are up for revision
  - All will be revised and drawn into one Handbook
  - Efforts will focus on cleaning chemistries, cleaning equipment, and how they are inter-dependent
  - Not much evolution in the semi-aqueous materials





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# 5-32: Cleanliness Assessment

# • 5-32a: Ionic Conductivity/Ion Chromatography TG

- John Radman, Trace Labs; Beverly Newton, Dionex
- Present Activities
  - Round robin tests aimed at ionic test methods that are reproducible and repeatable concentration on 2.3.28
  - Beginning work on a method for Bare Board Cleanliness by IC
    - Will become IPC-Tm-650, method 2.3.28.2
  - Other potential future work for Ion Chromatography
    - Users Guide for Ion Chromatography
    - Test methodology for spot extractions
    - Test methodology for small components







# 5-32: Cleanliness Assessment

# • 5-32b: Surface Insulation Resistance TG

- Chris Mahanna, Robisan Labs
- Present Activities
  - IPC-9201 Revision A (SIR Handbook) just published
  - Focusing on newer SIR test methodologies such as continuous monitoring, the 28 day HP test, J-STD-004 SIR flux qualification
  - Recently released method 2.6.3.7, which incorporates continuous monitoring
    - Can be used either for flux qualification or process qualification
    - Monitoring every 20 minutes for 96 hours minimum
  - Watching the Hewlett Packard 28 day electromigration test method
  - Working on accept/reject criteria for B-52 test board
  - Reviewing data from several UK/EU consortia efforts





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# 5-32: Cleanliness Assessment

#### • 5-32c: Bare Board Cleanliness Assessment TG

- Doug Pauls, Rockwell Collins
- Tutorial information
  - IPC-5701 Guidance for Purchasers Published
  - IPC-5702 Guidance for OEMs Published
  - IPC-5703 Cleanliness for Fabricators in draft stage
  - IPC-5704 Cleanliness Requirements for Bare Board Cleanliness draft
- Present Activities
  - Rockwell Collins IPC-B-52 Research Program
    - Bare Board Cleanliness by IC and SIR
    - Process Qualification by IC and SIR
  - Round robin studies for ion chromatography repeatability
  - Working on adopting the Delphi bare board cleanliness standard into IPC format will become IPC-5704
  - Working with ICTG on drafting the Delphi method into IPC format







## 5-32: Cleanliness Assessment

- 5-32e: Electrochemical Migration TG
  - Dr. Beverley Christian, RIM; Karl Sauter, Sun Microsystems
  - Responsible for:
    - All things related to electrochemical migration testing
    - Responsible for Conductive Anodic Filament (CAF) Resistance Test Method, 2.6.25 and associated Users Handbook
  - Present Activities
    - Has completed work on the CAF Resistance Method Users Handbook and has published this Handbook
    - Is reviewing data on the Hewlett Packard 28 day test method and other industry papers on CAF







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methodology

#### Paper from Apex 2006 has details of both

- - Board designed for SIR testing

- IEC: TB-57 board (version 7.1 is current)
- Two highly similar test vehicles developed

IPC-B-52 Research Program

- IPC: IPC-B-52 board

- Most IPC/IEC test coupons (e.g. B-24 board) are designed for material qualification on a common platform
- Co-operative effort between IPC and IEC IEC efforts being led by Graham Naisbitt, Gen3 Systems and Dr. Chris Hunt, NPL

Both IEC and IPE desire a process gualification test vehicle and test

Such boards often bear no resemblance to actual product

• Product: FR-4 (T<sub>G</sub> 170), solder mask, immersion silver

Similar to the TB-57, but with some additional coupons

• B-24: FR-4 (T<sub>G</sub> 140), bare copper, no solder mask





#### IEC-TB-57 Board









#### **IPC-B-52 Board**



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# **B-52 Bare Board Testing**

- Free Testing Yes, it says FREE
  - Rockwell Collins will test 5 bare boards IC, SIR, adhesion
  - Nice nifty report (yet to be developed)
  - PROVIDED You supply Doug with this information
    - Who you are, e.g. Farquart J. McGillicudy III, Whozit Corp
    - Fabricator and location, e.g. CPC, Cedar Rapids, IA
    - Solder mask, e.g. Taiyo PSR-4000, Type BN
    - Surface Finish and type, e.g. MacDermid Sterling ImAg
- 3 Companies have participated so far
- This information being collected to support development of bare board cleanliness standards
  - Correlating ion chromatography data with SIR performance







# Sample IC Report

RC Lab ID	Descr	F	Cl	NO2	Br	NO3	PO4	SO4	Total Halide	Total Anions
	<u>Set 2</u>									
040907-03	Sample 1	0.01	0.11	0.00	1.52	0.09	0.00	0.18	1.64	1.91
040907-04	Sample 2	0.01	0.07	0.00	0.76	0.00	0.00	0.18	0.84	1.02
040907-05	Sample 3	0.00	0.15	0.00	1.66	0.11	0.00	0.18	1.81	2.1
040907-06	Sample 4	0.01	0.09	0.00	1.17	0.07	0.00	0.18	1.27	1.52
040907-07	Sample 5	0.01	0.09	0.00	1.04	0.06	0.00	0.15	1.14	1.35
		0.01	0.10	0.00	1.00	0.07	0.00	0.17	1.24	1 50
		0.01	0.10	0.00	1.23	0.07	0.00	0.17	1.34	1.58







#### Sample SIR – FR4



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#### Sample SIR – Polyimide



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#### **Questions?**



